

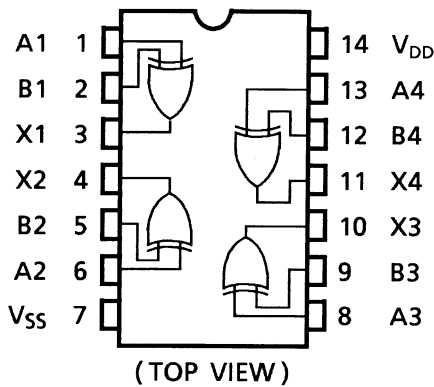
# TC4030BP, TC4030BF, TC4030BFN

## TC4030B Quad Exclusive-OR Gate

TC4030B contains four circuits of exclusive OR gates. Since the buffers of two stage inverters are provided for all the outputs, the input/output voltage characteristic has been improved and the noise immunity has been also improved. And increase of transmission time due to load capacity increase is kept minimum.

Wide variety of applicaitons are offered, such as digital comparators and parity circuits.

### Pin Assignment

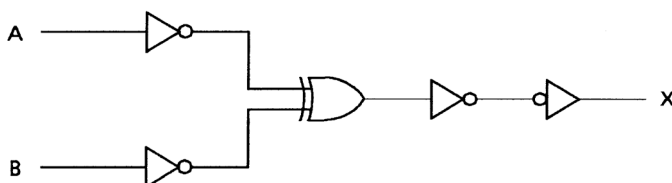


### Truth Table

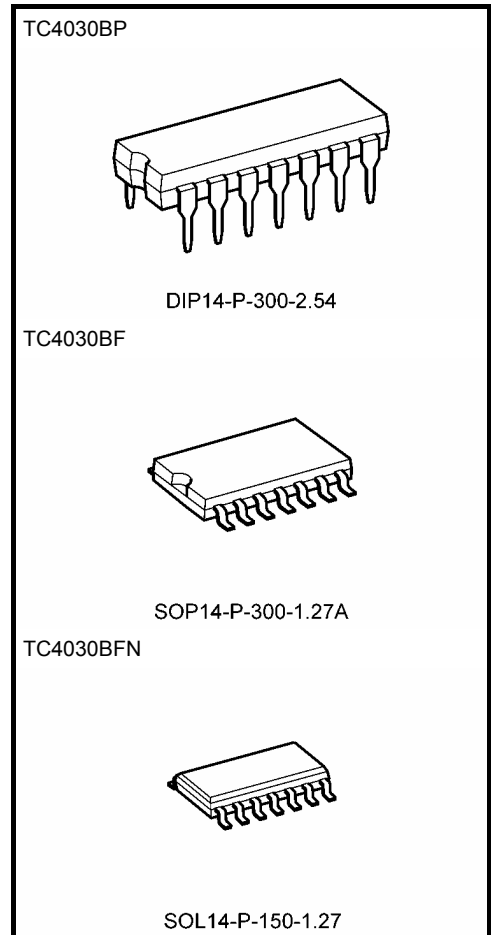
Inputs		Output
A	B	X
L	L	L
L	H	H
H	L	H
H	H	L

### Circuit Diagram

#### 1/4 TC4030B



Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight

DIP14-P-300-2.54	: 0.96 g (typ.)
SOP14-P-300-1.27A	: 0.18 g (typ.)
SOL14-P-150-1.27	: 0.12 g (typ.)

## Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	$V_{SS} - 0.5$ to $V_{SS} + 20$	V
Input voltage	$V_{IN}$	$V_{SS} - 0.5$ to $V_{DD} + 0.5$	V
Output voltage	$V_{OUT}$	$V_{SS} - 0.5$ to $V_{DD} + 0.5$	V
DC input current	$I_{IN}$	$\pm 10$	mA
Power dissipation	$P_D$	300 (DIP)/180 (SOIC)	mW
Operating temperature range	$T_{opr}$	-40 to 85	°C
Storage temperature range	$T_{stg}$	-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Operating Ranges ( $V_{SS} = 0$ V) (Note)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
DC supply voltage	$V_{DD}$	—	3	—	18	V
Input voltage	$V_{IN}$	—	0	—	$V_{DD}$	V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .

## Static Electrical Characteristics (V<sub>SS</sub> = 0 V)

Characteristics	Sym- bol	Test Condition	V <sub>DD</sub> (V)	-40°C		25°C			85°C		Unit	
				Min	Max	Min	Typ.	Max	Min	Max		
High-level output voltage	V <sub>OH</sub>	I <sub>OUT</sub>   < 1 μA V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub>	5	4.95	—	4.95	5.00	—	4.95	—	V	
			10	9.95	—	9.95	10.00	—	9.95	—		
			15	14.95	—	14.95	15.00	—	14.95	—		
Low-level output voltage	V <sub>OL</sub>	I <sub>OUT</sub>   < 1 μA V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub>	5	—	0.05	—	0.00	0.05	—	0.05	V	
			10	—	0.05	—	0.00	0.05	—	0.05		
			15	—	0.05	—	0.00	0.05	—	0.05		
Output high current	I <sub>OH</sub>	V <sub>OH</sub> = 4.6 V V <sub>OH</sub> = 2.5 V V <sub>OH</sub> = 9.5 V V <sub>OH</sub> = 13.5 V V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub>	5	-0.61	—	-0.51	-1.0	—	-0.42	—	mA	
			5	-2.50	—	-2.10	-4.0	—	-1.70	—		
			10	-1.50	—	-1.30	-2.2	—	-1.10	—		
			15	-4.00	—	-3.40	-9.0	—	-2.80	—		
Output low current	I <sub>OL</sub>	V <sub>OL</sub> = 0.4 V V <sub>OL</sub> = 0.5 V V <sub>OL</sub> = 1.5 V V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub>	5	0.61	—	0.51	1.2	—	0.42	—	mA	
			10	1.50	—	1.30	3.2	—	1.10	—		
			15	4.00	—	3.40	12.0	—	2.80	—		
Input high voltage	V <sub>IH</sub>	V <sub>OUT</sub> = 0.5 V, 4.5 V V <sub>OUT</sub> = 1.0 V, 9.0 V V <sub>OUT</sub> = 1.5 V, 13.5 V  I <sub>OUT</sub>   < 1 μA	5	3.5	—	3.5	2.75	—	3.5	—	V	
			10	7.0	—	7.0	5.50	—	7.0	—		
			15	11.0	—	11.0	8.25	—	11.0	—		
Input low voltage	V <sub>IL</sub>	V <sub>OUT</sub> = 0.5 V, 4.5 V V <sub>OUT</sub> = 1.0 V, 9.0 V V <sub>OUT</sub> = 1.5 V, 13.5 V  I <sub>OUT</sub>   < 1 μA	5	—	1.5	—	2.25	1.5	—	1.5	V	
			10	—	3.0	—	4.50	3.0	—	3.0		
			15	—	4.0	—	6.75	4.0	—	4.0		
Input current	"H" level	I <sub>IH</sub>	V <sub>IH</sub> = 18 V	18	—	0.1	—	10 <sup>-5</sup>	0.1	—	1.0	μA
	"L" level	I <sub>IL</sub>	V <sub>IL</sub> = 0 V	18	—	-0.1	—	-10 <sup>-5</sup>	-0.1	—	-1.0	
Quiescent supply current	I <sub>DD</sub>	V <sub>IN</sub> = V <sub>SS</sub> , V <sub>DD</sub> (Note)	5	—	1	—	0.001	1	—	7.5	μA	
			10	—	2	—	0.001	2	—	15.0		
			15	—	4	—	0.002	4	—	30.0		

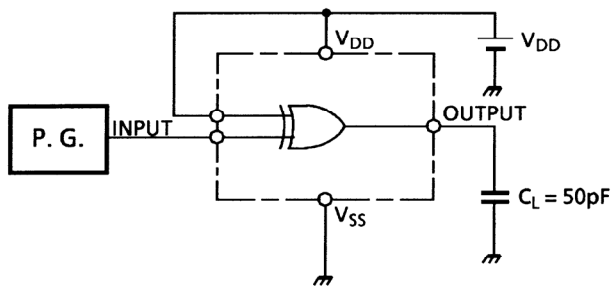
Note: All valid input combinations.

## Dynamic Electrical Characteristics (Ta = 25°C, VSS = 0 V, CL = 50 pF)

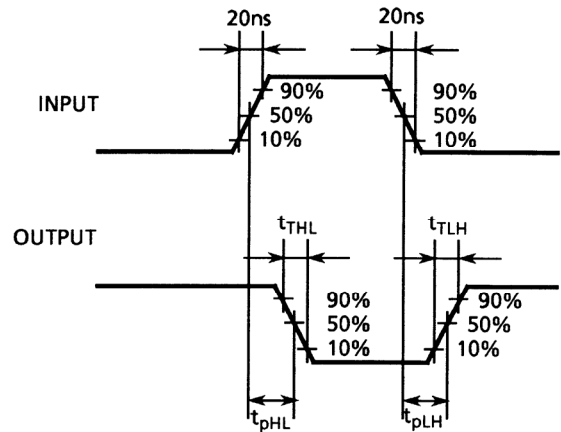
Characteristics	Symbol	Test Condition	VDD (V)	Min	Typ.	Max	Unit
			5	10	15	—	—
Output transition time (low to high)	t <sub>TLH</sub>	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Output transition time (high to low)	t <sub>THL</sub>	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Propagation delay time	t <sub>pLH</sub>	—	5	—	90	280	ns
	t <sub>pHL</sub>		10	—	45	130	
			15	—	35	100	
Input capacitance	C <sub>IN</sub>	—	—	5	7.5	pF	

## Circuit and Waveform for Measurement of Dynamic Characteristics

**Circuit**



**Waveform**



## Package Dimensions

DIP14-P-300-2.54

Unit : mm



Weight: 0.96 g (typ.)

**Package Dimensions**

SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL14-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

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20070701-EN GENERAL

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